

Notice of References Cited	Application/Control No. 10/085,145	Applicant(s)/Patent Under Reexamination MEISER ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,185,353	02-2007	Schlack, John A.	725/35
	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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